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For PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Atty. Docket No. 30320/14617A	Serial No. 10/728,404
		Applicant Doros, Theodore G.	
		Filing Date December 5, 2003	Group -2875 288 3

U.S. PATENT DOCUMENTS							
*Examiner Initials	Document Number	Issue Date	Name	Class	Subclass	Filing Date if Appropriate	
cmk	5361292	11-1-94	Sweatt	378	34		
cmk	5638211	6-10-97	Shiraishi	359	559		
cmk	6109756	8-29-00	Takahashi	359	857		
cmk	6233041	5-15-01	Shiraishi	355	53		
cmk	6452662	9-17-02	Mulkens et al.	355	67	4-6-99	
cmk	6525806	2-25-03	Smith	355	71	6-29-00	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)		
cmk		Sewell, "The Development of Step and Scan," Semiconductor Fabtech, 9 th Edition, pp. 193-197
cmk		Schellenberg et al., "Adoption of OPC and the Impact on Design and Layout," Session 7-4, Design Automation Conference, June 19, 2001
cmk		Rieger et al., "Layout Design Methodologies for Sub-Wavelength Manufacturing," Website, 20 pages, (undated), found at: http://videos.dac.com/videos/38th/7/7_3/7_3_slides.pdf
cmk		"Lithography Stepper Optics", Website, 10 pages, (undated), found at: http://www-inst.eecs.berkeley.edu/~ee290f/lithoslides.pdf
cmk		Hsu et al., "Dipole Decomposition Mask-design for Full Chip Implementation at the 100nm Technology Node and Beyond," Optical Microlithography XV, Proceedings of SPIE, Vol. 4691, © 2002, pp. 476-490

Examiner <i>Chris Kalwood</i>	Date Considered <i>August 10, 2004</i>
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	